# Hitesh Basantani

Portland, OR (Open to Relocation) · (814) 880-4925 · Hab186@gmail.com · linkedin.com/in/hiteshbasantani

#### **SUMMARY**

Experienced Engineering Leader and Data Scientist with over 15 years of expertise in hardware reliability, failure analysis, and predictive modeling for high-volume manufacturing environments, specializing in yield optimization. Proven track record in reducing failure rates and improving product quality through advanced statistical analysis and machine learning techniques. Extensive experience in cross-functional collaboration to optimize high-precision manufacturing processes. Currently pursuing a Master's in Data Science at UC Berkeley to deepen skills in data-driven approaches for enhancing hardware reliability.

#### **CORE COMPETENCIES**

- Hardware Reliability: Module Testing, Device Physics, Materials Science
- Failure Analysis & Root Cause Techniques: Outlier Detection, Time Series Analysis, SEM-EDX, Failure Mode and Effects Analysis (FMEA)
- Data Science & Statistical Research: Advanced Statistical Modeling, Machine Learning (Python, R, Scikit-learn, TensorFlow), Predictive Analytics
- Engineering Management & Program Leadership: Cross-Functional Team Leadership, Scope & Risk Management, Resource Planning, Hardware/Software Integration

#### **WORK EXPERIENCE**

Intel Corporation 2014 - Present

Staff Yield and Technology Development Engineer - Portland, OR

2018 - Present

- Developed and deployed end-to-end predictive neural network and XGBoost models using Python and PyTorch, reducing rejects by 90% and saving \$3.5M annually. Applied machine learning techniques to predict and prevent defects in modules, improving critical dimension (CD) accuracy and ensuring compliance with strict quality standards. Collaborated with automation and IT teams over a two-year project to fully integrate these solutions into production systems, enhancing process efficiency across all reticles.
- Utilized root cause analysis techniques such as SEM and EDX for failure identification and resolution.
   Implemented machine learning models to predict and eliminate critical process failures, including module defects, contributing to \$3 million in cumulative savings and an 80% yield improvement. Collaborated with cross-functional teams to successfully deploy the model.
- Led a cross-functional task force of 15 engineers, including dry etch, beam, and automation engineers, to resolve a critical module mismatch issue impacting technology performance in a \$1.3B facility. Successfully restored full operational capacity and **improved throughput by 12%** and restored full operational capacity within 4.5 months.
- Authored and standardized process documentation for mask production, coordinating 125 steps across two
  facilities. Reduced integration time by 30% through optimization of material transfer, quality control, and
  compliance procedures.
- Managed a team of 8 engineers during a manager's medical leave, meeting yield targets for two consecutive quarters and maintaining production quality across all product lines. Supported team goals while fulfilling technical duties.
- Chaired two inter-module teams (IMTs) focused on pattern placement and CD improvement projects, achieving
  a 0.3% yield improvement efficiency. Led cross-departmental initiatives to ensure product quality and
  operational efficiency.

### Process Technology Development Engineer (Module Reliability) - Portland, OR

2014 - 2018

- Developed advanced statistical models to optimize module performance and hardware reliability, increasing
  toolset uptime by 15% equivalent to the cost of a \$15M tool. Enhanced process consistency for high-precision
  modules.
  - Collaborated with the vendor to integrate data-driven adjustments into tool performance monitoring, reducing the need for frequent recalibrations and decreasing response times by 15%.

- Led cross-functional technical reviews as Chair of a module engineering committee, introducing new statistical
  control methods for module testing, resulting in a 5% reduction in defect rates and improved hardware
  reliability. Coordinated efforts across multiple teams to drive process improvements and ensure consistent
  product quality.
  - Worked with stakeholders from engineering and quality control to identify and resolve key issues affecting product yield, leading to sustainable quality improvements.

## **EDUCATION and AWARDS**

# University of California, Berkeley

Berkeley, CA

Master of Information and Data Science (Expected 2025)

## The Pennsylvania State University, University Park

University Park, PA

Ph.D., Engineering Science and Mechanics M.Sc., Engineering Science and Mechanics B.Sc., Engineering Science and Mechanics

# **Department and Division Awards:**

Award for Machine Learning Innovations in Critical Dimension Uniformity (Intel): Recognized for developing advanced machine learning models that significantly improved Critical Dimension Uniformity, enabling performance enhancements for Intel's next-generation wafer processing technology.

Award for Enhancing Tool Capability and Saving \$15M in Capital Expenditure (Intel): For optimizing existing toolsets to increase throughput (TPT), which eliminated the need for purchasing an additional \$15M tool, resulting in significant cost savings for Intel.

Outstanding Contribution Award for Improving Photomask Reliability (Intel): Received for making substantial contributions to improving the reliability of photomasks in production, which prevented a large number of Intel wafers from being scrapped, ensuring high production quality and efficiency for the life of the process.

### **TECHNICAL SKILLS & PROFICIENCIES**

**Programming & Data Science Tools Proficiency:** Python, R, SQL, TensorFlow, Scikit-learn, PyTorch, Docker, Git, Poetry, XGBoost

Programming & Data Science Tools Familiarity: AWS, Google Cloud, SQL, Kubernetes, PySpark, Hadoop

Product Analytics & Experimentation: A/B Testing, Experimentation Design, User Behavior Analysis

Project Management & Leadership: Agile Methodologies, Jira, MS Project, Cross-Functional Team Leadership